

PATENT NUMBER

U.S. UTILITY Patent Application

O.I.P.E. SCANNED <i>QAN</i> Q.A. <i>CS</i>	PATENT DATE
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APPLICATION NO. 09/627456	CONT/PRIOR F	CLASS 356	SUBCLASS 11	ART UNIT 2851	EXAMINER P112
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TS Kazuki Yokota

Overlay mark, method of measuring overlay accuracy, method of making alignment and semiconductor device therewith

PTO-2040
12/99

ISSUING CLASSIFICATION											
ORIGINAL				CROSS REFERENCE(S)							
CLASS		SUBCLASS		CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)						
INTERNATIONAL CLASSIFICATION											

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<input type="checkbox"/> TERMINAL DISCLAIMER	DRAWINGS			CLAIMS ALLOWED	
	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G.
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<input type="checkbox"/> The term of this patent shall not extend beyond the expiration date of U.S. Patent. No. _____ _____ _____	_____ (Primary Examiner) (Date)			ISSUE FEE	
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